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Application/Control No.	Applicant(s)/Patent under Reexamination	r
10/829,529	HOYTE ET AL.	
Examiner	Art Unit	
Thomas K. Pham	2121	

	SEAR	CHED	
Class	Subclass	Date	Examiner
700	28	3/2/2006	TP
700	29,31	3/2/2006	TP
700	18,23	3/2/2006	TP
700	37	3/2/2006	TP
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Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST searched	3/2/2006	TP
Inventors searched	3/2/2006	TP
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